

NEWS RELEASE

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EDN Magazine Names the WaferSense® Auto Vibration System (AVS) From CyberOptics Semiconductor an EDN Innovation Award Finalist

A team of technical editors at EDN recently selected the AVS as a finalist in the metrology category of the 19th EDN Innovation Awards. The annual competition is produced by EDN to honor “a diverse group of electronics engineers and the groundbreaking products they have produced,” according to EDN’s Website.

The wireless AVS sensor travels -- just as a wafer would -- through process tools and automation equipment to track the real-time acceleration and vibration a wafer experiences. Engineers use AVS’ three-axis data to protect deposition uniformity and optimize both yield and equipment productivity, reducing qualification time and maintenance expenses.

- To vote for the [AVS](#), scroll to the bottom of the following Web page: <http://www.edn.com/innovationballot.asp>

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